

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)		
30	0.010 at V _{GS} = 10 V	30	26.5 nC		
30	0.018 at V _{GS} = 4.5 V	25	20.5 110		

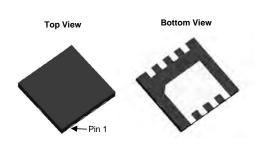
FEATURES

- · Halogen-free
- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested

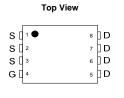


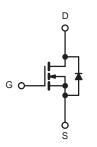
APPLICATIONS

- DC/DC Conversion
 - Low-Side Switch
- Notebook PC
- Gaming



DFN 3x3 EP





N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V_{GS}	± 20	v	
	T _C = 25 °C		30		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C]	22.6		
Continuous Diam Current (1) = 100 O)	T _A = 25 °C	l _D	21.5 ^{b, c}		
	T _A = 70 °C		17.1 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	100	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	I ₂	13		
Continuous Source-Drain Diode Current	T _A = 25 °C	ls —	3.1 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	10		
Avalanche Energy	L=0.11IIII	E _{AS}	5	mJ	
	T _C = 25 °C		16.7		
Maximum Power Dissipation	T _C = 70 °C	P _D	10.7	W	
Maximum Fower Dissipation	T _A = 25 °C	'D	3.7 ^{b, c}	VV	
	T _A = 70 °C	1	2.4 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	27	34	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	6	7.5	C/ V V	

- a. Based on T_C = 25 °C. b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 85 °C/W.



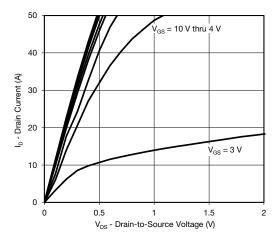
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	ΔVps/Tμ		27		mc\ //0:	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- I _D = 250 μA		- 5.6		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oata Valta va Brain Oamant	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10 µ		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
		V _{GS} = 10 V, I _D = 15 A		0.010		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 10 A		0.018			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 15 A		75		S	
Dynamic ^b					I	ı	
Input Capacitance	C _{iss}			650		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		236			
Reverse Transfer Capacitance	C _{rss}	1		20			
Total Gate Charge	Q _g	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A	10	10	20	nC	
				4.5	9		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		2.1			
Gate-Drain Charge	Q _{gd}			0.7			
Gate Resistance	R _g	f = 1 MHz	0.2	1.1	2.2	Ω	
Turn-On Delay Time	t _{d(on)}			8	16	ns	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		16	30		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		17	35		
Fall Time	t _f			7	15		
Turn-On Delay Time	t _{d(on)}			14	30		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		50	100		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	30		
Fall Time	t _f			8	18		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			13		
Pulse Diode Forward Current ^a	I _{SM}				100	Α	
Body Diode Voltage	V _{SD}	I _S = 3 A			1.2	V	
Body Diode Reverse Recovery Time	t _{rr}				40	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	1 - 10 A dl/dt - 100 A/vo T - 05 °C			20	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		12.5			
Reverse Recovery Rise Time	t _b			7.5		ns	

Notes:

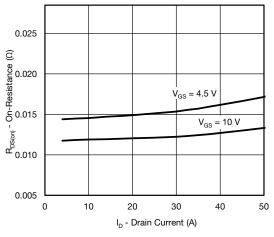
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

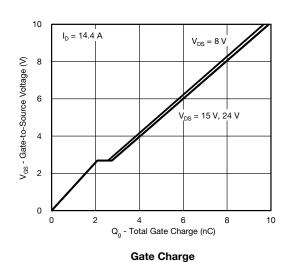


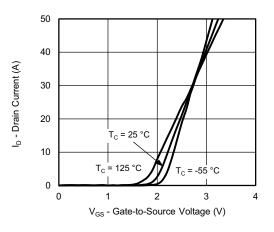


Output Characteristics

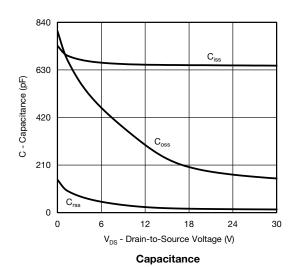


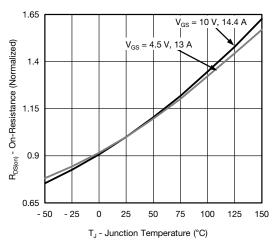
On-Resistance vs. Drain Current





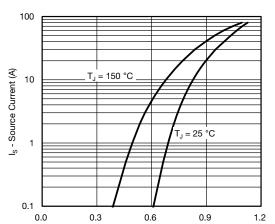
Transfer Characteristics



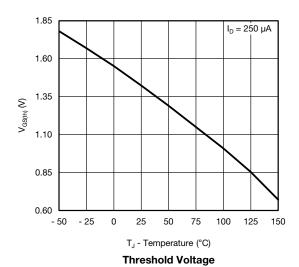


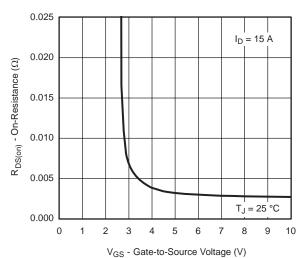
On-Resistance vs. Junction Temperature

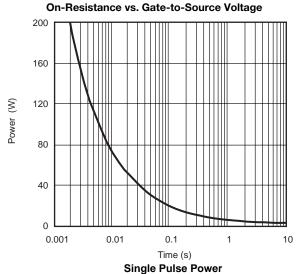




${ m V}_{ m SD}$ - Source-to-Drain Voltage (V) ${ m {\bf Source-Drain \ Diode \ Forward \ Voltage}}$



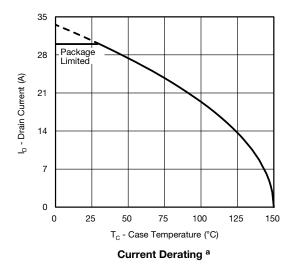


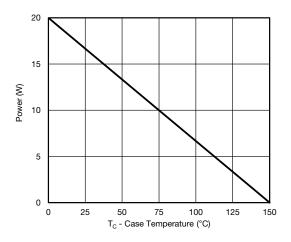


(3) timited by Poscoling 1 100 µs 1 100 µs 1 100 ms 100 ms

$$\begin{split} &V_{DS}\text{-} \text{Drain-to-Source Voltage (V)} \\ &^{\star}V_{GS}>\text{minimum }V_{GS}\text{ at which }R_{DS(on)}\text{ is specified} \end{split}$$
 Safe Operating Area, Junction-to-Ambient







Power, Junction-to-Case

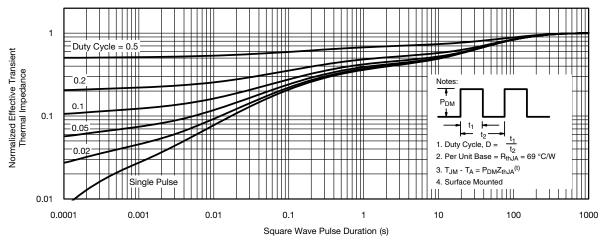
Note

a. The power dissipation P_D is based on T_J max. = 25 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

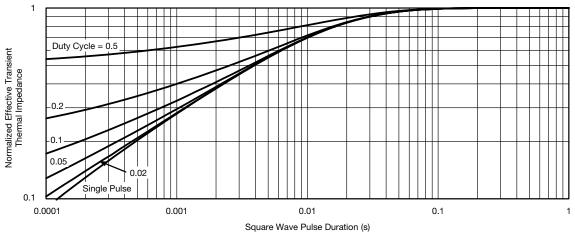
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5





Normalized Thermal Transient Impedance, Junction-to-Ambient

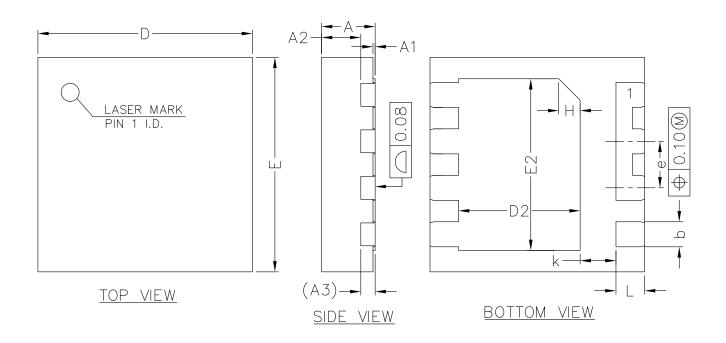


Normalized Thermal Transient Impedance, Junction-to-Case

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6







COMMON DIMENSIONS
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX		
Α	0.70	0.75	0.80		
A1	0.00	0.02	0.05		
A2	0.50	0.55	0.60		
А3	0.20REF				
b	0.30	0.35	0.40		
D	2.90	3.00	3.10		
Е	2.90	3.00	3.10		
D2	1.60	1.70	1.80		
E2	2.30	2.40	2.50		
е	0.55	0.65	0.75		
K	0.40	0.50	0.60		
L	0.35	0.40	0.45		



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